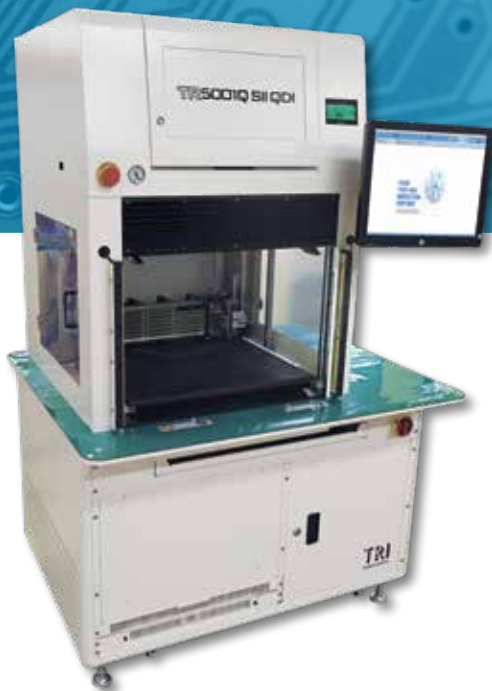


TR5001 SII SERIES

MULTI CORE SERIES



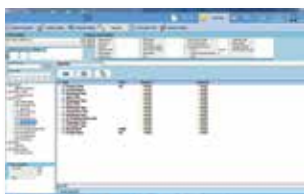
- Multi-Core Parallel Test
- Non-Multiplexing 1:1 per Pin Architecture
- Scalable MDA to ICT and Functional Test
- High Accuracy and High Throughput
- Durable Quick Disconnection Interface
- Automatic Conveyor Width Positioning
- Board Warp and Mis-Alignment Notification

INLINE/MANUAL HANDLER
ICT WITH FUNCTIONAL TEST

TR5001 SII SERIES FEATURES



Real Image Display



Customizable Test Plan



Clear Parallel Test Interface



Flash Programming



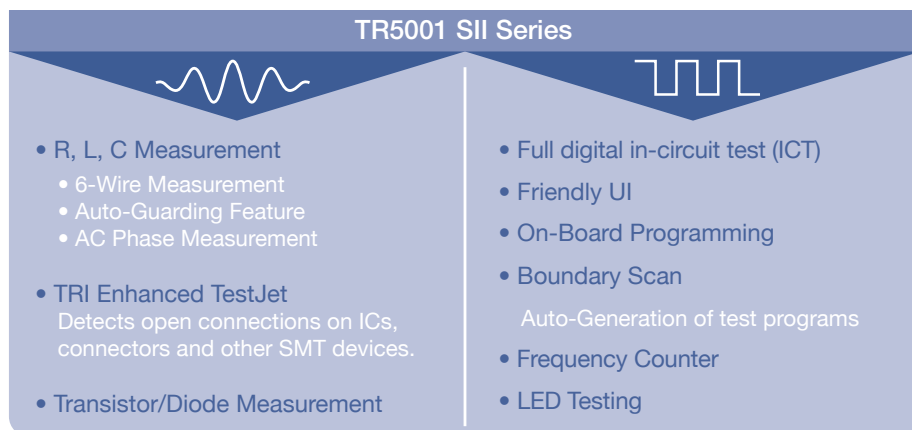
TRI Enhanced TestJet

The Next Generation In-Circuit Test Strategy

Non-Multiplexing Pin Design, 1:1 Driver/Receiver to Pin Ratio.

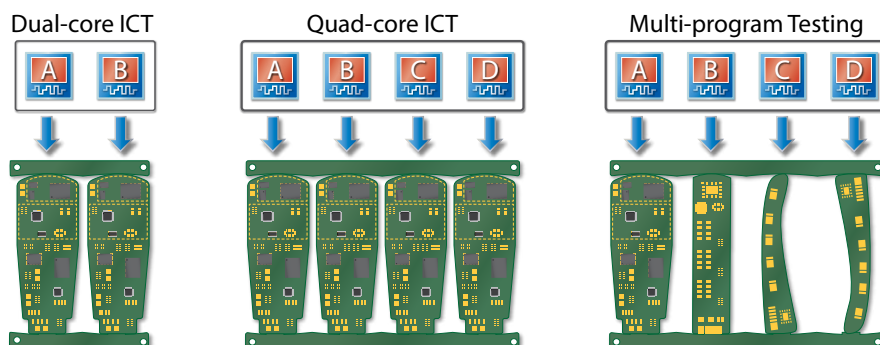
- Optimized Nail Placement with 1:1 Ratio Flexibility
- 1:1 per-pin Driver/Receiver ratio for the fastest test program development and debugging
- Improved Test Accuracy and Capability

The most flexible ICT+FCT solution in the market. TR5001 SII series can integrate with external instruments for functional tests such as: PXI, Labview,etc.



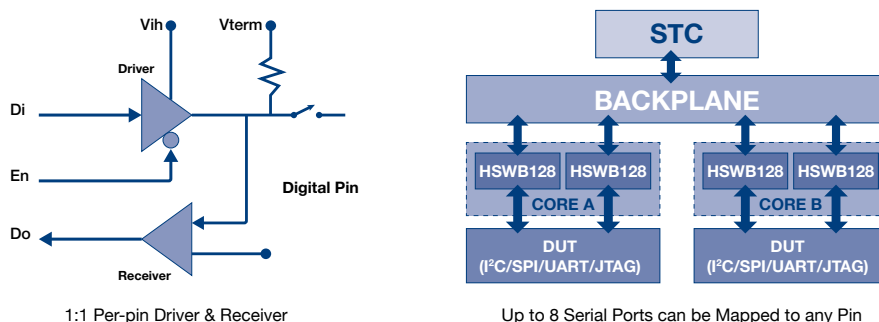
Multi-Core Parallel Testing Design

The new TR5001 SII series testers support up to four independent test cores for high-throughput parallel testing. Depending on tested product complexity, tester cores can be merged to test higher pin-count boards.



Multiple Serial Bus Access

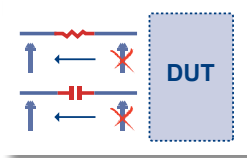
The TR5001 SII testers feature a new Serial Test Controller, which offers two high-speed serial ports per tester core, for a maximum of 8 individual ports. Each of these serial ports can be mapped to any test pin on TR5001 SII's Hybrid Switching Board and deliver a variety of Serial Bus protocols (I²C, SPI, UART, JTAG) to the DUT.



Limited Access Test Solutions

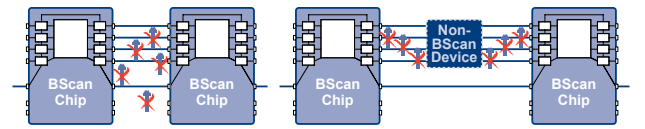
Drive Through Test

Greatly reduces test probes for passive analog components connected in series with JTAG and BScan capable devices and connectors.



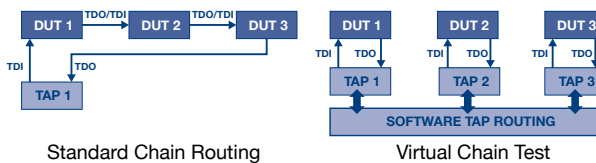
Boundary Scan Test

Virtual nails tests for RAM, ROM, TTL and TREE devices, and IEEE1149.6 Test.



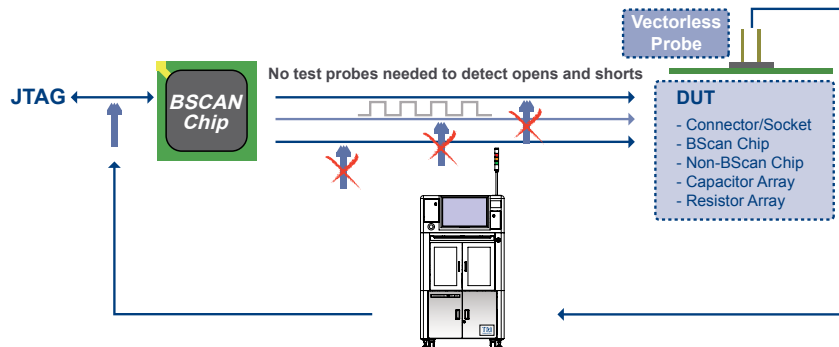
Boundary Scan Virtual Chain Test using BSCAN2 Module

Simplify chained DUT testing using software TAP routing in TRI Virtual Chain BScan Test. Reduce fixture wiring and test program complexity.



TRI ToggleScan Test

A Powerful vectorless test technology that significantly reduces the number of test probes, ToggleScan utilizes BScan and vectorless probes to test non-BScan devices.

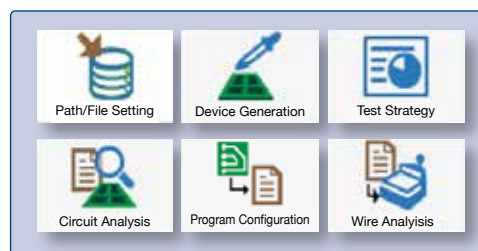


Shop Floor System Support

TR5001 SII Series can integrate with many shop floor systems to help centralize production line management and improve production quality using gathered testing data.

Intelligent Software Interface

The TR5001 SII Series features an intuitive software interface designed for easy operation and programming. Enhanced Automated features include Automated Test Program Generator, Auto-tuning, and setting templates.

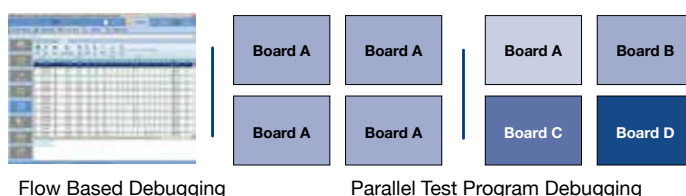


ATPG

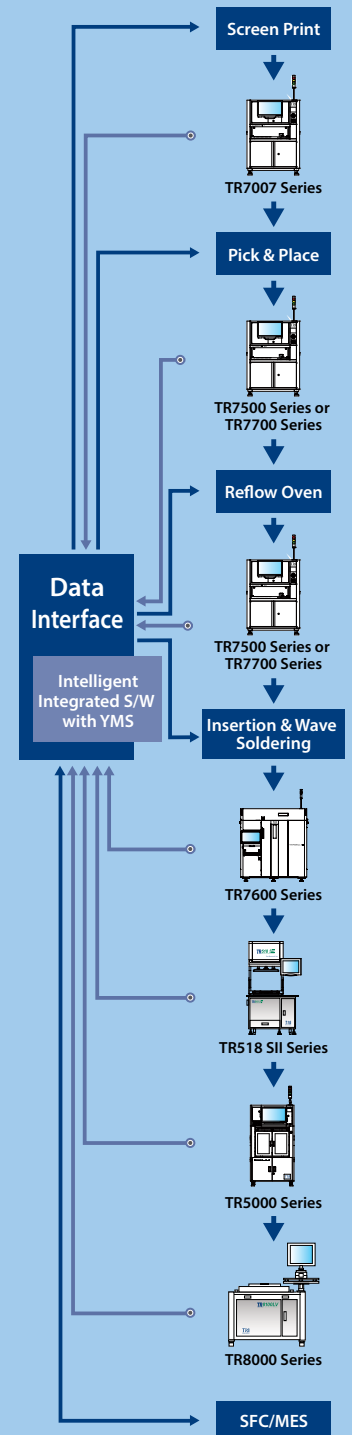
The advanced programming assistant helps generate fixture wiring and test programs based on CAD data and BOM input files.

Easy Debugging

The new test program debugging interface supports flow-based test program debugging of individual or parallel test programs. Using multiple cores, it is now possible to debug both panel boards or individual boards.



Yield Management System



Data Flow Feedback Flow

- Inspection results and data integration
- Real time SPC and production yield management
- Quality reports and closed loop tracking
- Support defect component analysis and improvements
- Knowledge Management (KM)
- Productivity and Quality Management

General

Multicore/Single Core Test

	TR5001 SII INLINE TR5001 SII QDI TR5001 SII	TR5001D SII INLINE TR5001D SII QDI TR5001D SII	TR5001Q SII INLINE TR5001Q SII QDI TR5001Q SII
(cores)	1	1, 2	1, 2, 4
Maximum Analog/Hybrid Test Points	3456	3328	4096
Operating System	Microsoft® Windows compatible PC with USB, Windows 10		
Power Requirement	200 – 240 VAC, Single Phase, 50/60 Hz 3 kVA		
Air Requirement	Dry Air 4 – 8 kg/cm ² , Air Consumption: 20 liters/cycle		
Fixture Type	Inline or offline with long lifespan Quick Disconnection Interface. Offline press type (TR5001D/Q SII)		

PCB and Conveyor System

PCB Size	
Standard	(W) 450 x (L) 300 x (H) 0.6 – 5 mm (W) 17.7 x (L) 11.8 in.]
Min.	(W) 70 x (L) 70 mm [(W) 2.76 x (L) 2.76 in.]
Max. PCB Weight	2 kg (4.41 lbs) [5 kg (11.02 lbs) optional]
Component Height Limitations	
Top Surface of Conveyor	90 mm (3.54 in.)
Bottom Surface of Conveyor	30 mm (1.18 in.)
Conveyor Height	890 – 1000 mm* (35.0 – 39.4 in.)*

* SMEMA Compatible Inline Conveyor

Analog Hardware

Measurement Switching Matrix	6-wire measurement
Programmable Frequency	100 Hz, 1 kHz, 10 kHz, 100 kHz
Programmable DC Voltage Source	±10V max, Resolution: 10 mV
Programmable DC Current Source	+100 mA max, Resolution: 0.2 mA
Programmable AC Voltage Source	10 Vpp max, Resolution: 10 mV
Programmable High Voltage Current Source	53 V / 100 mA max

Component Measurement Capability

Resistance	30 mohm – 40 Mohm
Capacitance	5 pF – 40 mF
Inductance	5 µH – 60 H

Analog Measurement

AC Voltmeter	0 – 100 Vp
DC Voltmeter	0 – ±100 V; Resolution: 2.5 mV – 50 mV
DC Ammeter	1 µA – 100 mA; Resolution: 30 nA – 30 µA

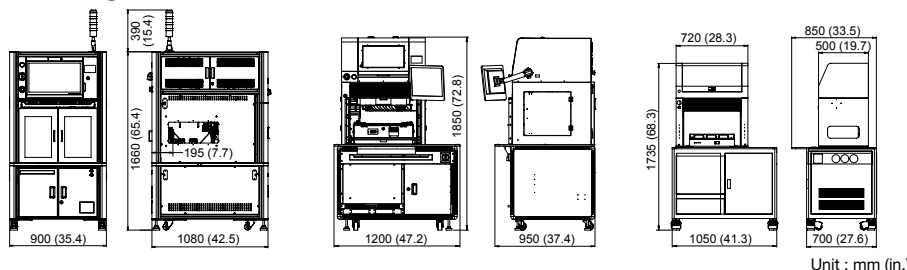
Optional Hardware

Analog Test	
TestJet Technology	Vectorless open circuit detection
Arbitrary Waveform Generator (AWG)	Frequency Range 0 – 100 kHz; Resolution: 0.15 Hz, BW: 100KHz max

Digital Test

Non-multiplexing 1:1 per pin architecture	with independent per-pin level setting
Pin Drivers	Programmable levels 0.5 V to 4 V
Pin Receivers	Programmable levels 0 V to 5 V
Pull-up/Pull-down Resistor	4.7 K
DUT Power Supplies	5 V@3 A, 3.3 V@3 A, 12 V@3 A, -12 V@1 A and 24 V@3 A
APPS Programmable DUT Power Supply	75 V / 8 A max, 200W maximum output power
On-board Programming of Flash & EEPROM Memories	
MAC Address Programming	Supports MAC address programming with server supplied MAC address
Boundary Scan	Includes BScan Chain Test, BScan Cluster Test, BScan Virtual Nails Test, BScan Virtual Chain Test and IEEE1149.6 Test
ToggleScan Test	Advanced test technology that combines with BScan and Vectorless test functions to detect pin open or short issues
Tree Test Facilities with BGA Test	Pattern generator for detection of pin opens for BGA/VLSI chips

Dimensions/Weight



	TR5001D/Q SII INLINE TR5001 SII INLINE	TR5001D/Q SII QDI TR5001 SII QDI	TR5001D/Q SII TR5001 SII
Weight	670 kg (1477 lbs)	700 kg (1543 lbs)	300 kg (661 lbs)

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